Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination DE VAAN, ADRIANUS JOHANNES STEPHANES MA	
10/529,732		
Examiner	Art Unit	

Andrew Kong

2851

SEARCHED					
Class	Subclass	Date	Examiner		
353	84,20,30,3 1,34,88,89 ,97	2/26/2007	AK		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search (USPGPUB,USOCR,USPAT EPO,JPO)	2/26/2007	AK		
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